

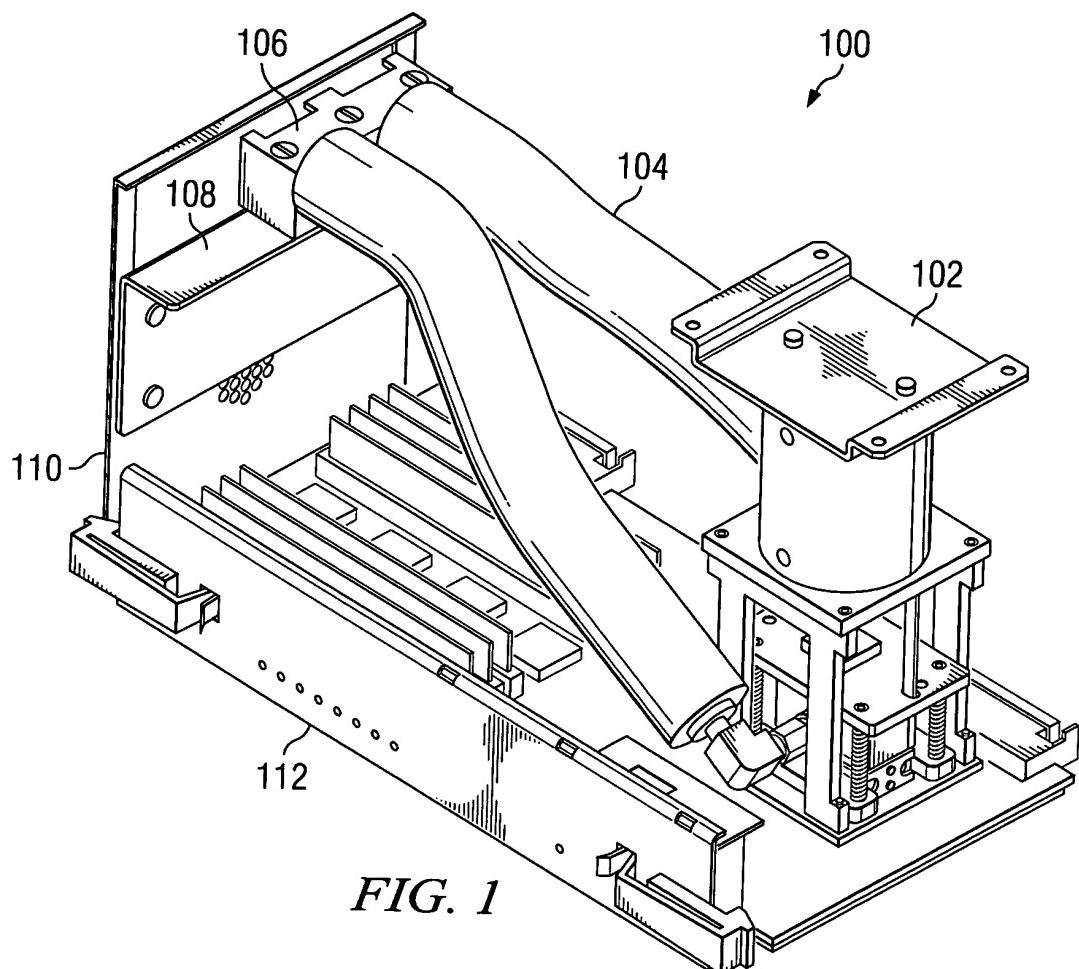
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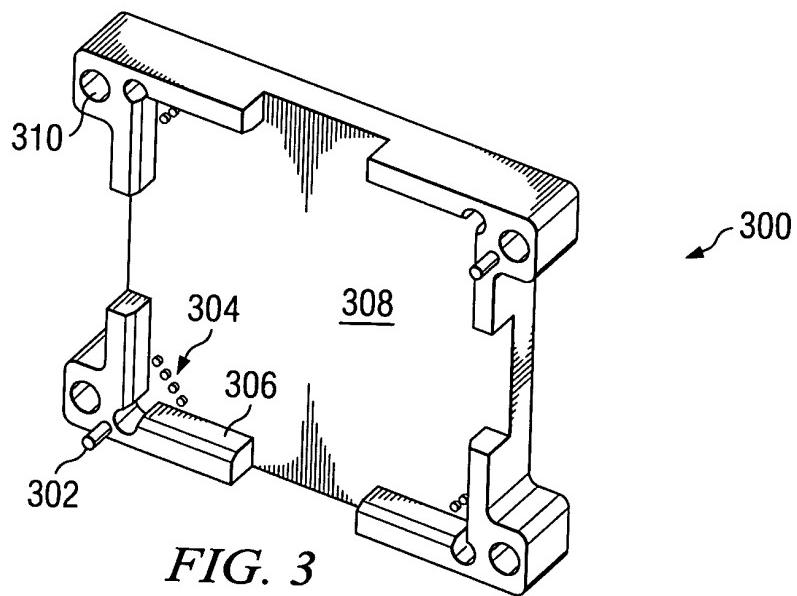
Apparatus For Functional and Stress Testing  
of Exposed Chip Land Grid Array Devices

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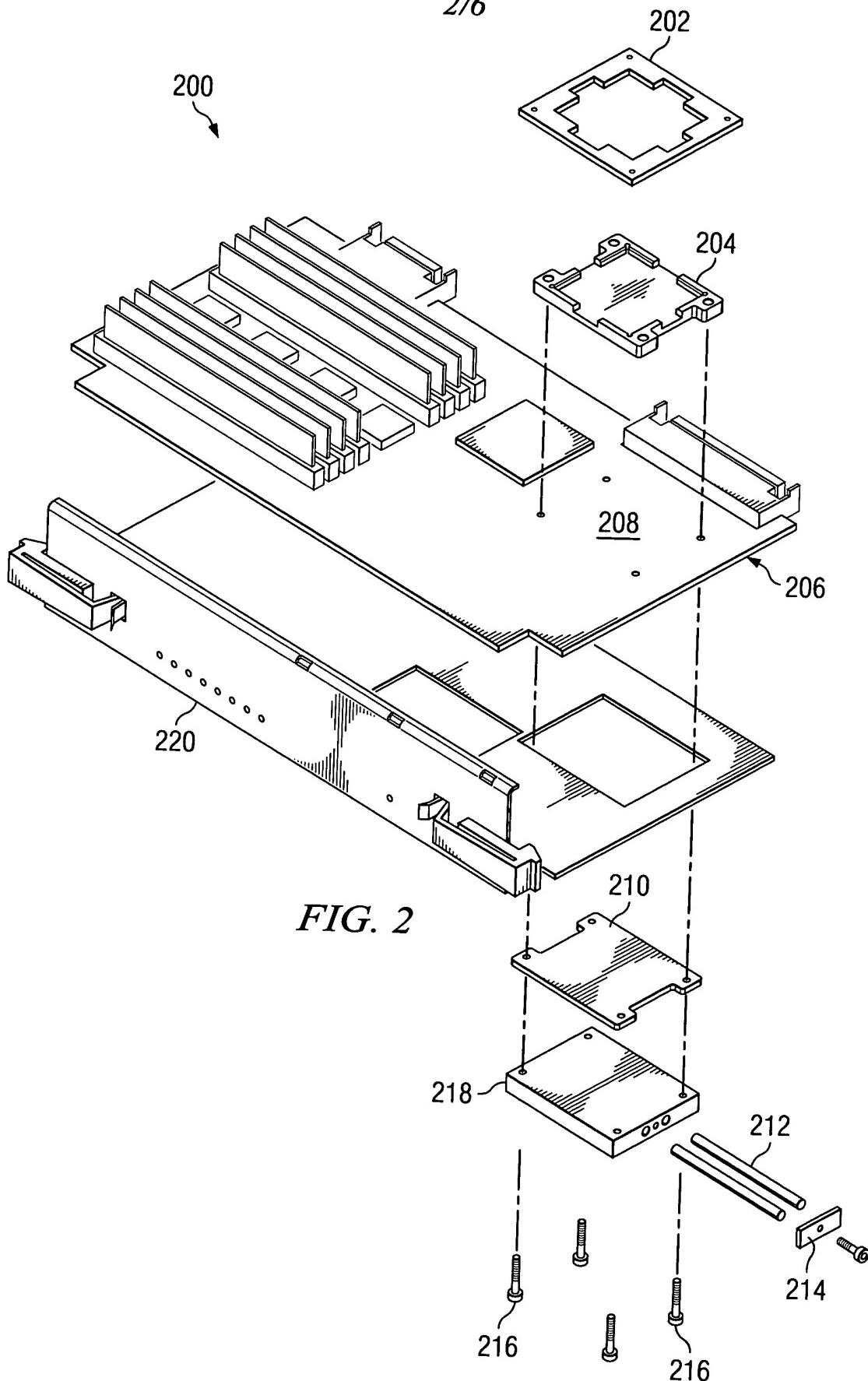
*FIG. 1*



*FIG. 3*

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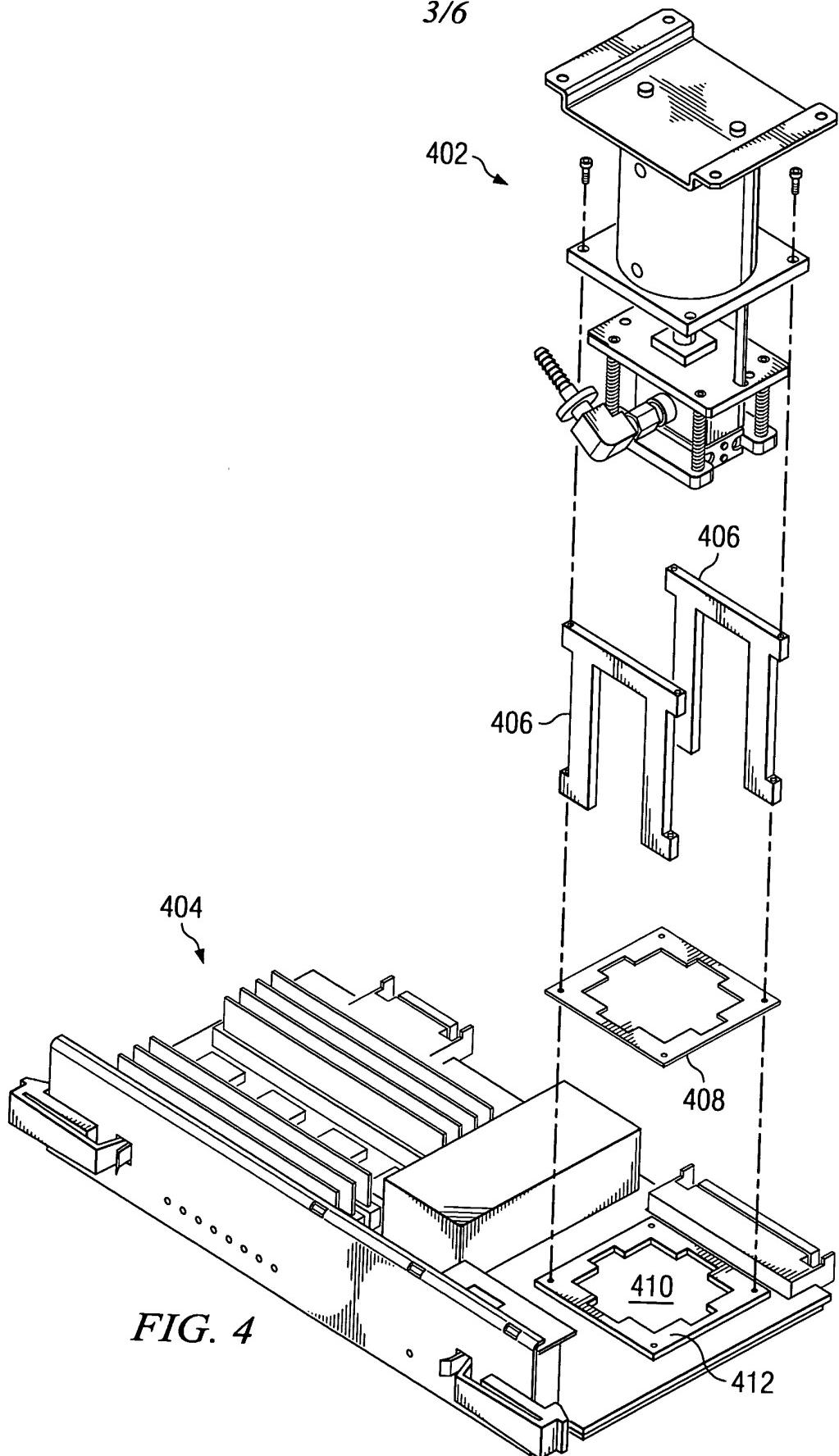
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*FIG. 2*

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*FIG. 4*

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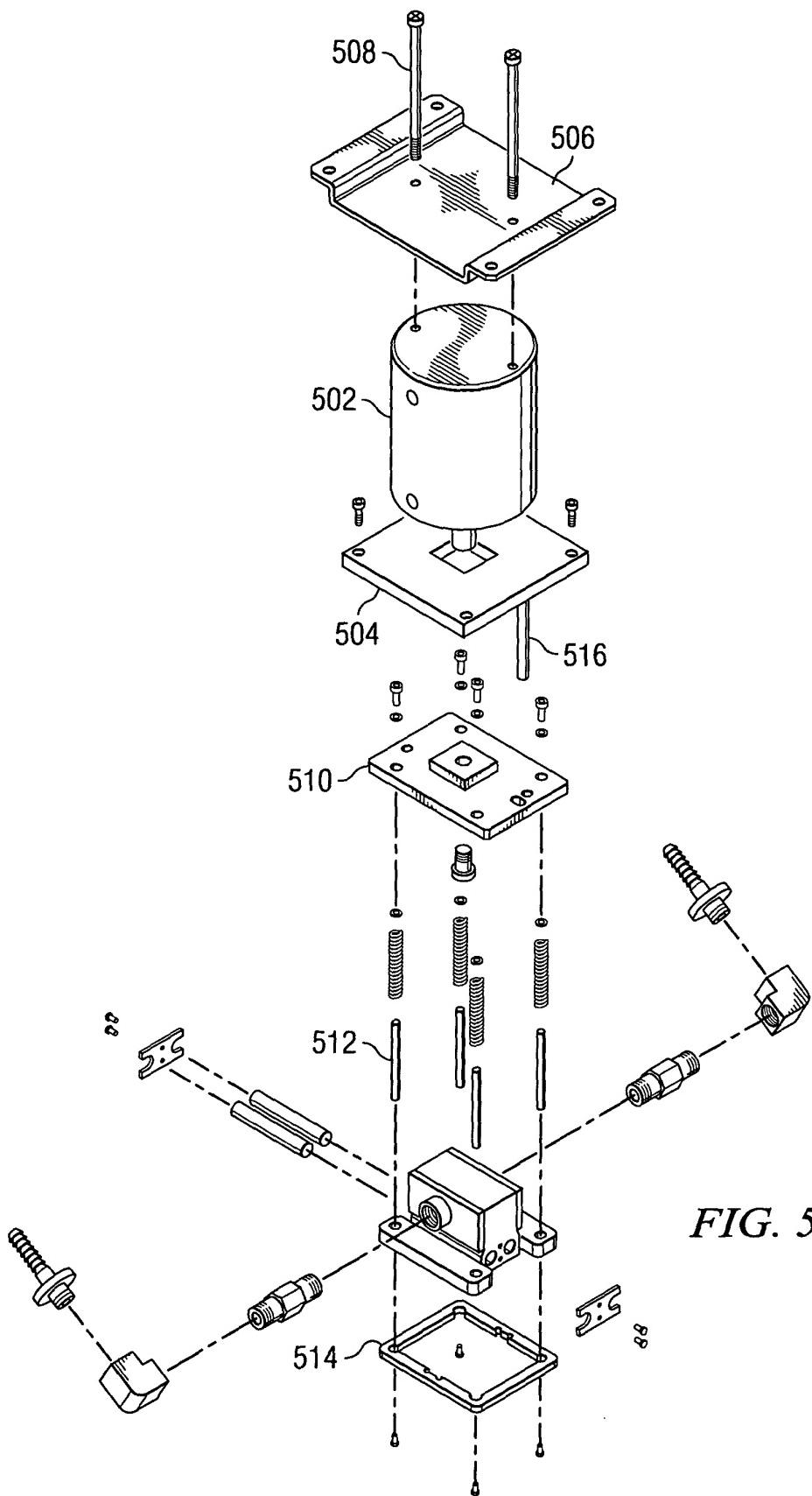
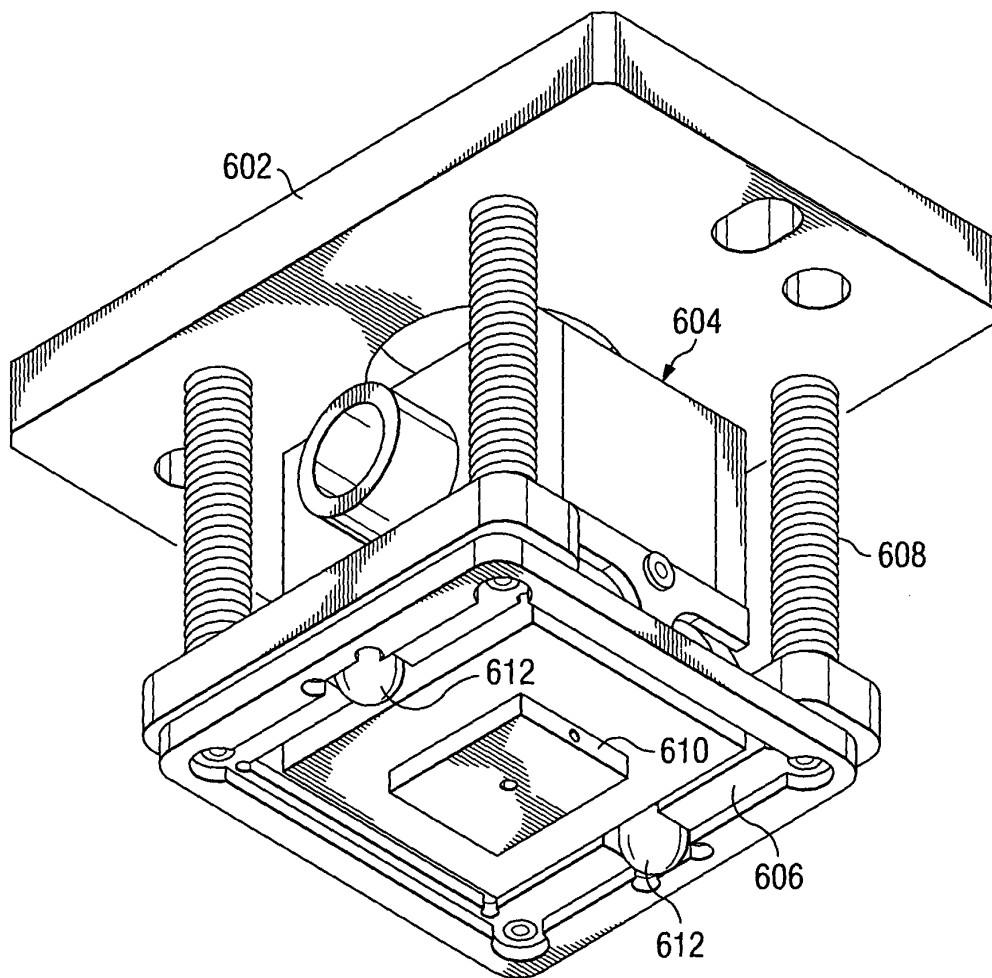


FIG. 5

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*FIG. 6*

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of Exposed Chip Land Grid Array Devices

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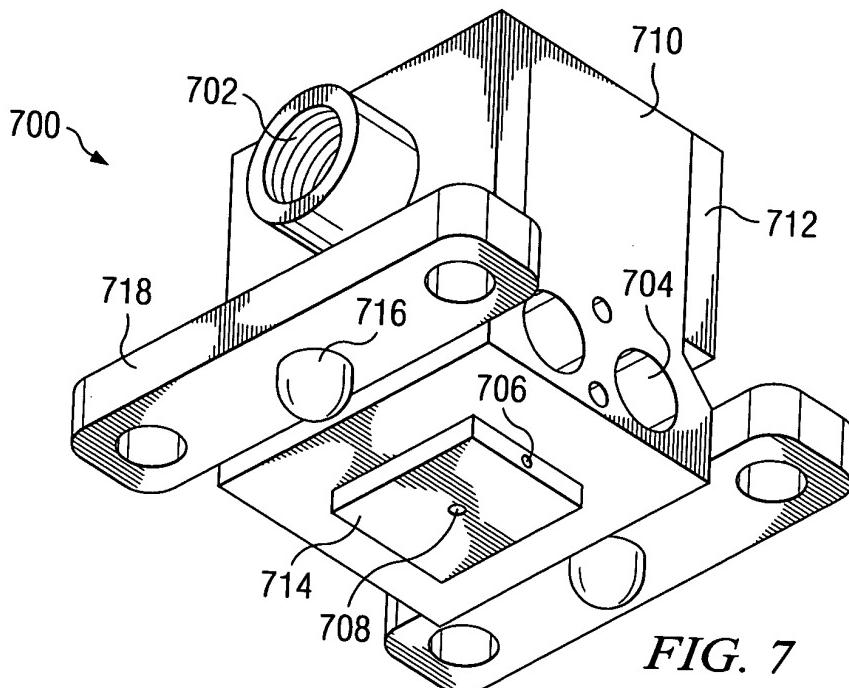


FIG. 7

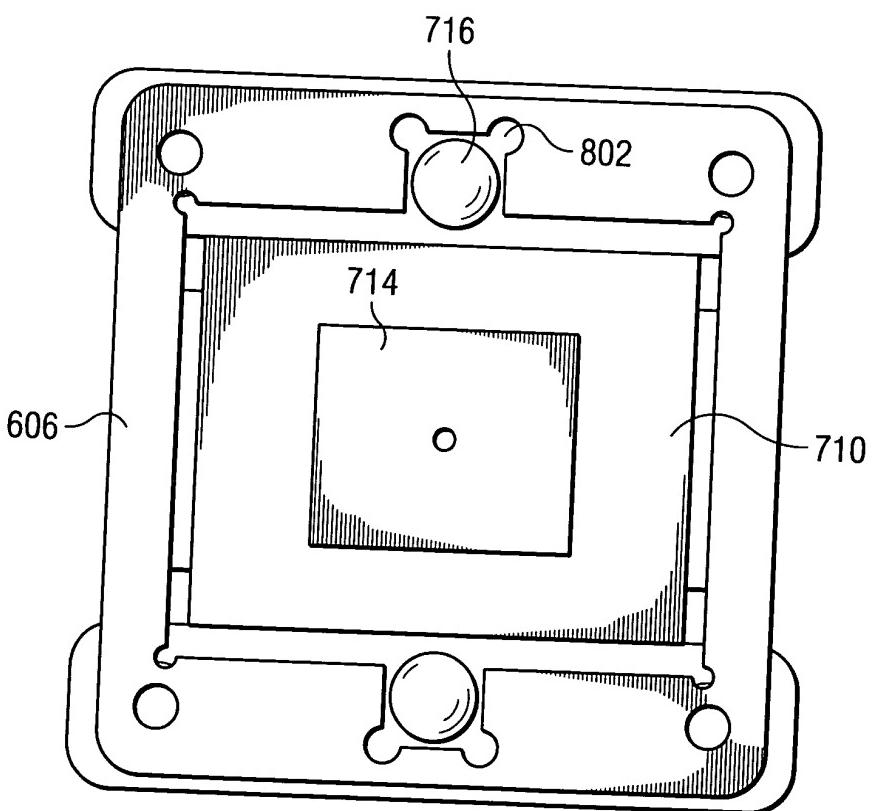


FIG. 8